

(19)



JAPANESE PATENT OFFICE

## PATENT ABSTRACTS OF JAPAN

(11) Publication number: **2001014975 A**(43) Date of publication of application: **19.01.01**

(51) Int. Cl. **H01H 13/78**  
**G01R 31/00**  
**G06F 3/02**  
**H01H 65/00**

(21) Application number: **11185788**(22) Date of filing: **30.06.99**(71) Applicant: **OPTREX CORP HIROSHIMA OPT KK**(72) Inventor: **TOYODA YUZO**(54) **CONTACT INSPECTING METHOD FOR MATRIX SWITCH**

Thus, a determining portion determines whether each contact is normal.

(57) Abstract

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**PROBLEM TO BE SOLVED:** To speedily perform a contact inspection by operating a switch, so that a column of signal line provides contact information of one contact to input the contact information from whole columns of signal lines to a receiving portion without duplicating, and determining, with a determining portion, whether each contact is normal, based on the contact information from this each column of signal line.

**SOLUTION:** When contacts are arranged regularly in a lattice pattern with a matrix switch 11, as a switch pressing means, two or more switch-on plates formed linearly so as to simultaneously come into contact with a plurality of contacts are used. By arranging respective switch-on plates in parallel along diagonal lines (two-dot chain lines shown by oblique lines) of the matrix switch 11, moving them, and lowering them down, contact information of one contact is provided from a column of signal line.

